

PRODUCT / PROCESS CHANGE NOTIFICATION

SO8N capacity increase at ST Shenzhen: SHD assembly line introduction for RF EEPROM products

What is the change?

STMicroelectronics MMY Division is pleased to announce the capacity increase of the SO8N at ST Shenzhen (China) assembly & test plant. In this purpose, the SHD (**S**uper **H**igh **D**ensity) assembly line, already qualified for other EEPROM product families, will be used for RF EEPROM products.

Why?

The strategy of STMicroelectronics Memory Division is to support our customers on a long-term basis. In line with this commitment, the qualification of the SO8N SHD assembly line in ST Shenzhen for RF EEPROM products will increase the production capacity and consequently improve the service to our customers.

When?

The assembly of the ST25 Dynamic tags (ST25DV / M24LR / M24SR) range 6 products in SO8N on the SHD line will ramp up from May 2018. Range 8 products will ramp up from September 2018.

How will the change be qualified?

The SO8N SHD assembly line at ST Shenzhen will be qualified for RF EEPROM products following the standard STMicroelectronics Corporate Procedures for Quality and Reliability.

What is the impact of the change?

- Form: Bottom side showing ejector pin mark on products assembled on SHD line
- Fit: no change
- Function: no change

How can the change be seen?

- BOX LABEL MARKING

The change is visible on the BOX LABEL MARKING, inside the Finished Good Part Number:

→ Example for M24LR64E-RMN6T/2

nics	Manu Country Of O Pb-free MSL: 1	-			
2	PBT: 260 °C	Category: e4	ECOPACK2/ROHS		
ctre		LR64E-RMN6 ⁻ _R64EMN6T2			
icroelectron	Total Qty:	2500	Mask revision: "H" for SHD assembly "G" for current version		
õ	Trace Codes	PPYWWLLL WX T	F		
<u>D</u>	Marking	24LFERB			
STM		XOXOOXXXOOO			

Appendix A- Product Change Information

Product family / Commercial products:	ST25D products family SO8 package including ST25DVxxx, M24LRxxx and M24SRxxx
Customer(s):	All
Type of change:	Package assembly process
Reason for the change:	Capacity increase
Description of the change:	SHD assembly line for SO8N at ST Shenzhen
Forecast date of the change: (Notification to customer)	Week 13 / 2018
Forecast date of <u>Qualification samples</u> availability for customer(s):	See Appendix B
Forecast date for the internal STMicroelectronics change, <u>Qualification Report</u> availability:	Qualification report will be available from May 2018 (Range 6) and September 2018 (Range 8) Qualification plan is available and included in this document in Appendix C
Marking to identify the changed product:	Date code (date to be communicated upon ST qualification)
Description of the qualification program:	Standard ST Microelectronics Corporate Procedures for Quality and Reliability
Product Line(s) and/or Part Number(s):	See Appendix B
Manufacturing location	ST Shenzhen (China)

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Appendix B: Concerned Commercial Part Numbers:

Commercial Part Numbers	Package	Samples Availability	Estimated date of first shipment
M24SR02-YMN6T/2	SO8N	May 2018	May 2018
M24SR04-YMN6T/2	SO8N	May 2018	May 2018
M24SR16-YMN6T/2	SO8N	May 2018	May 2018
M24SR64-YMN6T/2	SO8N	May 2018	May 2018
M24SR64-YMN8T/2	SO8N	September 2018	September 2018
M24LR04D-WMN8T/2	SO8N	September 2018	September 2018
M24LR04E-RMN6T/2	SO8N	May 2018	May 2018
M24LR16D-WMN8T/2	SO8N	September 2018	September 2018
M24LR16E-RMN6T/2	SO8N	May 2018	May 2018
M24LR64E-RMN6T/2	SO8N	May 2018	May 2018
ST25DV04K-IER6S3	SO8N	May 2018	May 2018
ST25DV04K-IER8S3	SO8N	September 2018	September 2018
ST25DV16K-IER6S3	SO8N	May 2018	May 2018
ST25DV16K-IER8S3	SO8N	September 2018	September 2018
ST25DV64K-IER6S3	SO8N	May 2018	May 2018
ST25DV64K-IER8S3	SO8N	September 2018	September 2018

Appendix C: Qualification Plan:

	Test short description					
Test	Method	Conditions	Sample Size / lot	No. of lots	Duration	Acceptance criteria
	Preconditioning: mo	visture sensitivity level 1				
PC	JESD22-A113 / J-STD-020E	MSL1, peak temperature at 260 °C, 3 IReflow	333	3 lots by product (2)	N/A	0 fail / 333
тнв	Temperature humidi	ty bias				
(1)	JESD22-A101	85 °C, 85% RH, <u>bias</u> Vcc max	77	3 lots by product (2)	1000 <u>hrs</u>	0 fail / 77
тс	Temperature cycling]				
(1)	JESD22-A104	- 65 °C / +175 °C	77	3 lots by product (2)	500 cy	0 fail / 77
тмѕк	Thermal shocks					
(1)	JESD22-A106	-55°C / +125 °C	25	3 lots by product (2)	200 shocks	0 fail / 25
AC	Autoclave (pressure	pot)				
(1)	JESD22-A102	121 °C, 100% RH at 2 ATM	77	3 lots by product (2)	96 <u>hrs</u>	0 fail / 77
HTSL	High temperature st	orage life				
(1)	JESD22-A103	High Temperature Storage at 150 °C	77	3 lots by product (2)	1000 <u>hrs</u>	0 fail / 77
ESD	Electrostatic discha	rge (machine model)				
CDM	ANSI/ESDA/ JEDEC JS-002-2014	Field induced charging method	18	1 lot by product (2)	N/A	0 fail / 18



Note (1) : THB-, TC-, TMSK-, AC-, HTSL- dedicated parts are first subject to preconditioning flow. Note (2) : Products used for qualification are : M24SR64, M24LR64, ST25DV64

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Document Revis	ion Hist	ory
Date	Rev.	Description of the Revision
February 20 , 2018	1.00	First draft creation

e Documents & Reference Documents		
Rev.: Date:	Source document Title	